

**Pending Claims:**

Following is a complete listing of the claims pending in the application:

1-16. (Canceled)

17. (Withdrawn) A method for interfacing a relatively small number of electrical devices to be tested with a high volume testing device comprising the acts of:  
attaching a first set of contacts to the testing device;  
removably fixing a second set of contacts in contact with the first set of contacts;  
attaching a removable electrical socket to the second set of contacts; and  
placing a device to be tested within the socket.

18. (Withdrawn) The method of claim 17, further comprising testing the device.

19. (Withdrawn) The method of claim 17 wherein attaching the first set of contacts to the testing device includes removably clamping the first set of contacts to the testing device.

20. (Withdrawn) The method of claim 17 wherein removably fixing the second set of contacts in contact with the first set of contacts includes frictionally engaging the first set of contacts with the second set of contacts.

21. (Withdrawn) The method of claim 17 wherein the removable electrical socket is a first removable electrical socket, and the method further comprises:  
detaching the first removable electrical socket from the second set of contacts;  
and  
attaching a second removable electrical socket to the second set of contacts.

22. (Withdrawn) The method of claim 17, further comprising:

removing the second set of contacts from contact with the first set of contacts;  
and  
removably fixing a third set of contacts in contact with the first set of contacts, the  
third set of contacts being configured differently from the second set of  
contacts.

23. (Withdrawn) The method of claim 17, further comprising:  
removing the first set of contacts from the testing device; and  
attaching a third set of contacts to the testing device, the third set of contacts  
being configured differently from the first set of contacts.

24. (Withdrawn) A method for interfacing an electrical device socket having  
pins to a testing apparatus having a load board, comprising:  
removably attaching a plurality of flexible, electrically conductive first contacts to  
a base member, the first contacts having first portions and second  
portions, the second portions being resiliently laid against a surface of the  
base;  
engaging the first portions of the first contacts with corresponding electrical  
contacts on the load board;  
engaging the plurality of first contacts with a plurality of second contacts by  
frictionally engaging first sections of the second contacts with the second  
portions of the first contacts; and  
electrically coupling each of a plurality of pin receptacles with one of the plurality  
of second contacts, the pin receptacles being oriented to removably  
receive the pins of the electrical device socket.

25. (Withdrawn) The method of claim 24 wherein the first contacts are  
removably attached to the base member by clamping the first contacts to the base  
member.

26. (Withdrawn) The method of claim 24 further comprising receiving the pins of the electrical device socket in the pin receptacles.

27. (Withdrawn) The method of claim 26 further comprising removing the pins of the electrical device socket from the pin receptacles.

28. (Withdrawn) The method of claim 26 further comprising engaging the first portions of the first contacts with the corresponding electrical contacts on the testing apparatus.

29. (Withdrawn) The method of claim 24 wherein removably attaching the first contacts to the base comprises clamping a first set of the plurality of first contacts against a first surface of the base member and clamping a second set of the plurality of first contacts against an opposing second surface of the base member.

30. (Withdrawn) The method of claim 29 wherein the first set of first contacts is clamped against the first surface of the base member with a first clamp and the second set of first contacts is clamped against the second surface of the base member with a second clamp.

31. (Withdrawn) The method of claim 29 wherein engaging the plurality of first contacts with the plurality of second contacts comprises frictionally engaging the first sections of a first set of the plurality of second contacts with the second portions of the first set of first contacts and frictionally engaging the first sections of a second set of the plurality of second contacts with the second portions of the second set of first contacts.

32. (Previously presented) A method of making a testing device, comprising:  
coupling a load board to a base member;  
removably coupling multiple electrically conductive first contacts to the base member, the first contacts having first portions that are thereby operatively

coupled to the load board and second portions that are operatively couplable to multiple second contacts;  
operatively coupling the second contacts to the second portions of the first contacts; and  
configuring at least one pin receptacle to be operatively couplable to at least one of the second contacts and to receive pins of an electrical socket device.

33. (Previously presented) The method of claim 32 wherein removably coupling the first contacts to the base member includes removably coupling the first contacts to the base member via at least one clamp.

34. (Previously presented) The method of claim 32 wherein operatively coupling the second contacts to the second portions of the first contacts includes frictional engaging the second contacts with the second portions of the first contacts.

35. (Previously presented) The method of claim 32, further comprising operatively coupling the at least one pin receptacle to the at least one of the second contacts.

36. (Previously presented) The method of claim 32, further comprising coupling the pins of the electrical socket device to the at least one pin receptacle.

37. (Previously presented) A method of making a testing device, comprising:  
coupling a load board to a base member;  
removably coupling multiple electrically conductive first contacts to the base member, the first contacts having first portions that are thereby operatively coupled to the load board and second portions that are operatively couplable to multiple second contacts;  
operatively coupling the second contacts to the second portions of the first contacts; and

configuring at least one pin receptacle to be operatively couplable to at least one of the second contacts and to receive pins of an electrical socket device, the electrical socket device being configured to receive a device to be tested.

38. (Previously presented) The method of claim 37 wherein removably coupling the first contacts to the base member includes removably coupling the first contacts to the base member via at least one clamp.

39. (Previously presented) The method of claim 37 wherein operatively coupling the second contacts to the second portions of the first contacts includes frictional engaging the second contacts with the second portions of the first contacts.

40. (Previously presented) The method of claim 37, further comprising operatively coupling the at least one pin receptacle to the at least one of the second contacts.

41. (Previously presented) The method of claim 37, further comprising coupling the pins of the electrical socket device to the at least one pin receptacle.